

MgB₂ Hot Electron Bolometers for Array Receivers

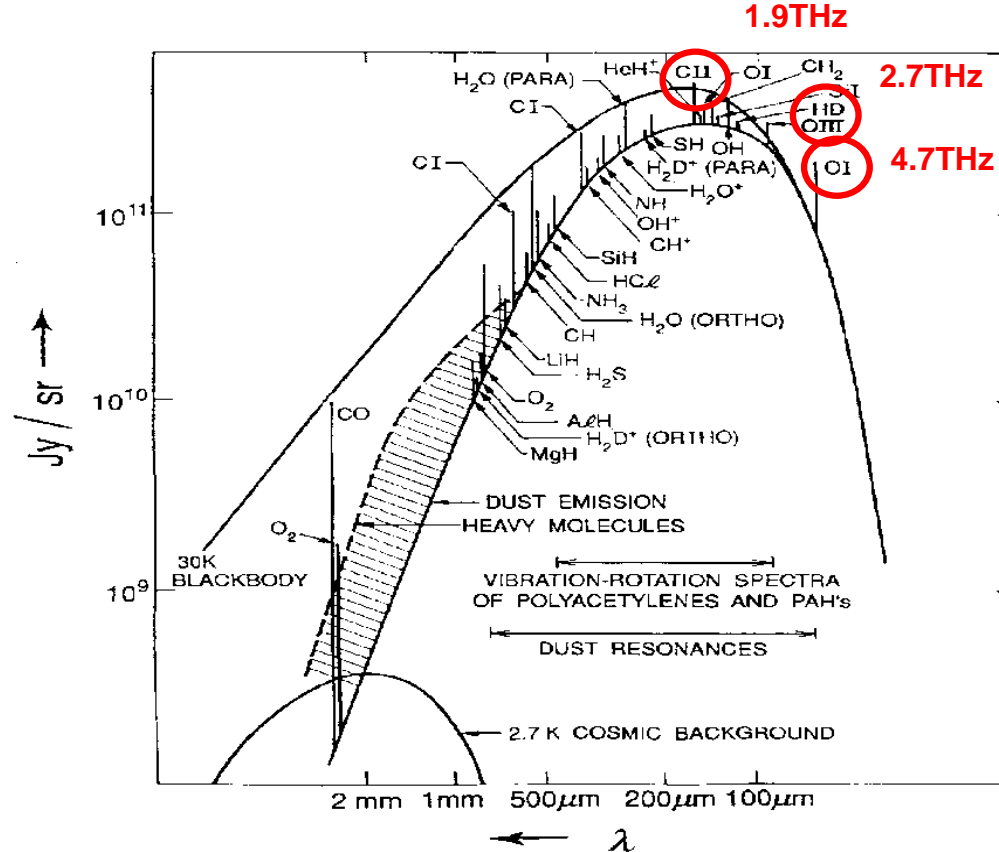
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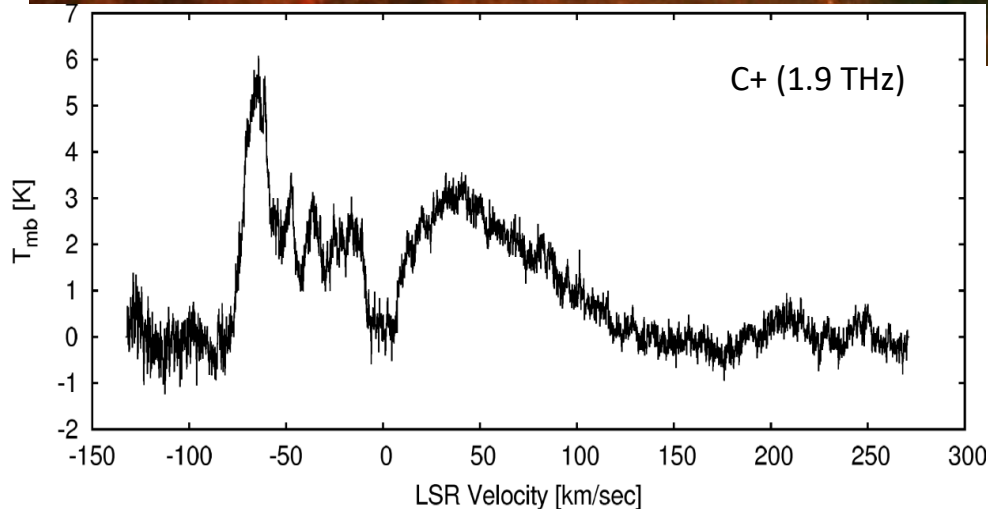
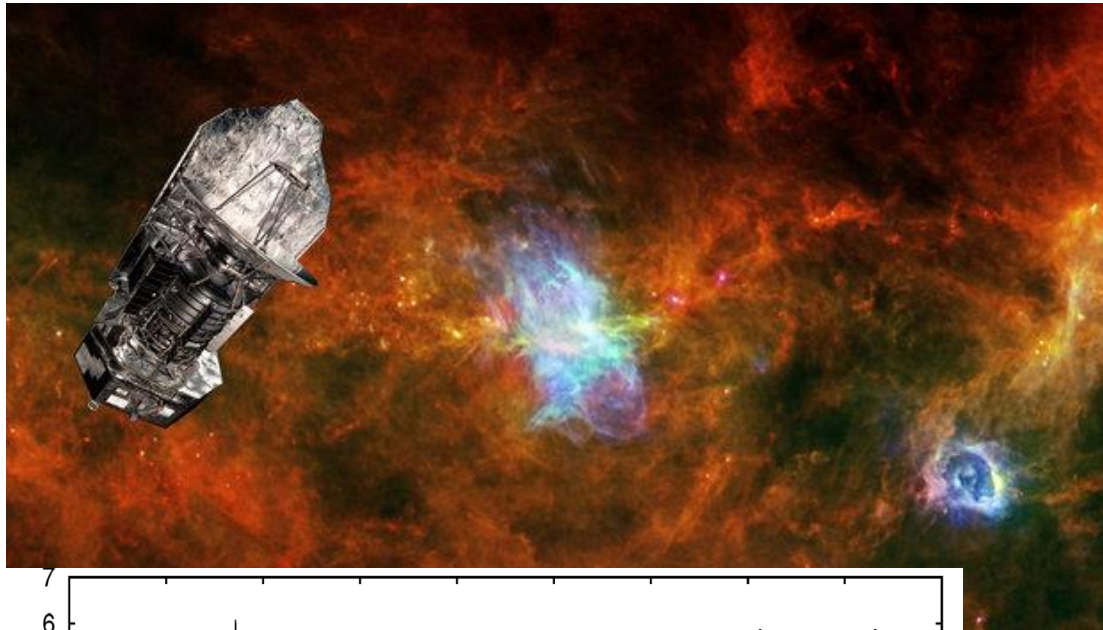
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Science Targets of Interest:



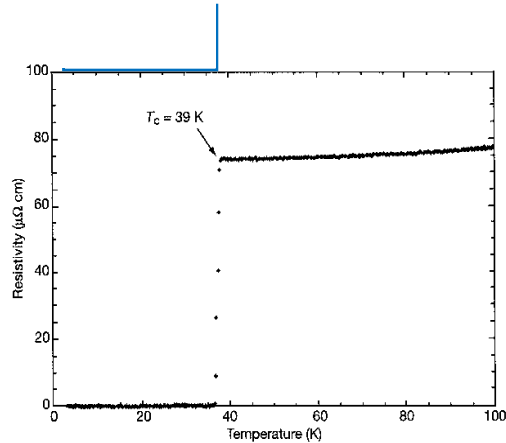
- HEB operation at elevated temperature which can be achieved by 20-25 K mechanical cryocoolers (in space)
- Achieving higher than in the state of the art NbN mixers IF bandwidth in order to enable spectroscopic measurements of highly Doppler broadened THz lines (up to 8-10 GHz is required).

Larger Bandwidth Needed at Higher Frequencies

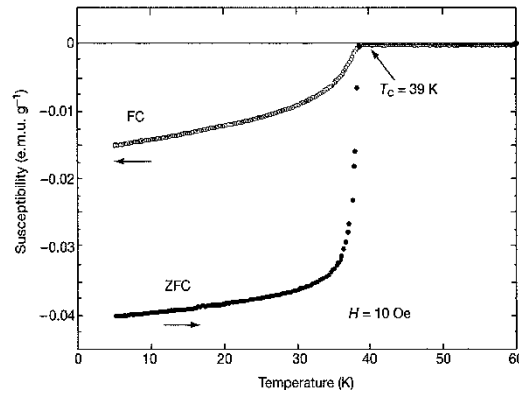


- Using Herschel HIFI, a scan of GC at 1.9 THz had features spanning 450 km/sec.
- $\Delta f = \frac{\Delta v}{c} f_0$
- A similar scan for the 4.7 THz OI line would require over 7 GHz to obtain the same velocity span.

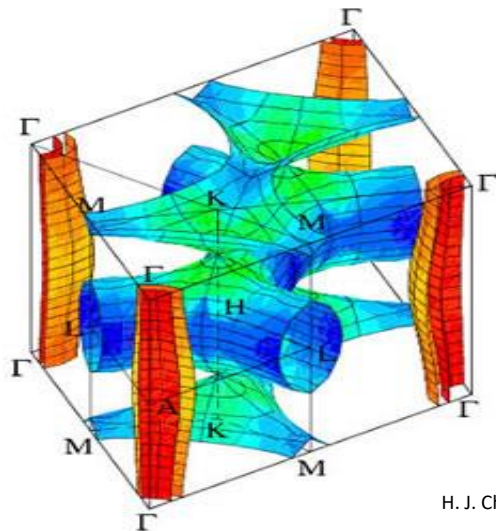
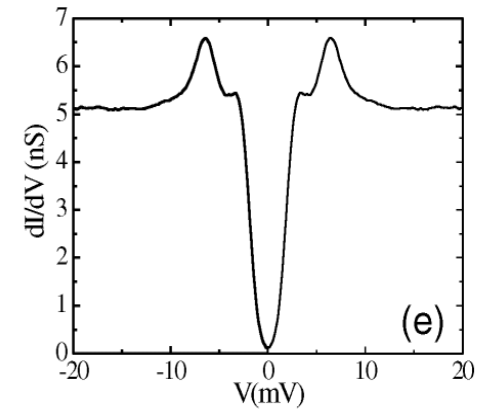
Superconductivity in MgB_2



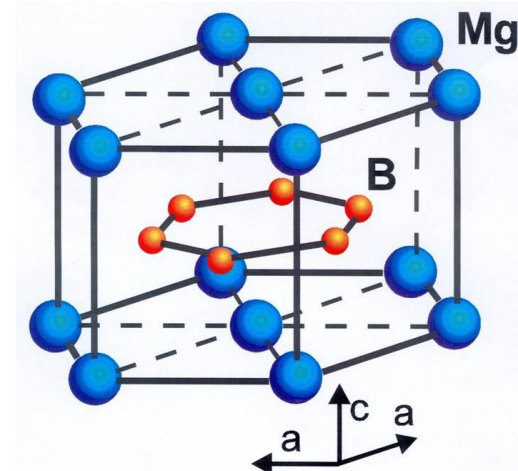
J. Nagamatsu et al., Nature **410**, 63 (2001).



M. Iavarone et al., Phys. Rev. Lett. **89**, 187002 (2002).

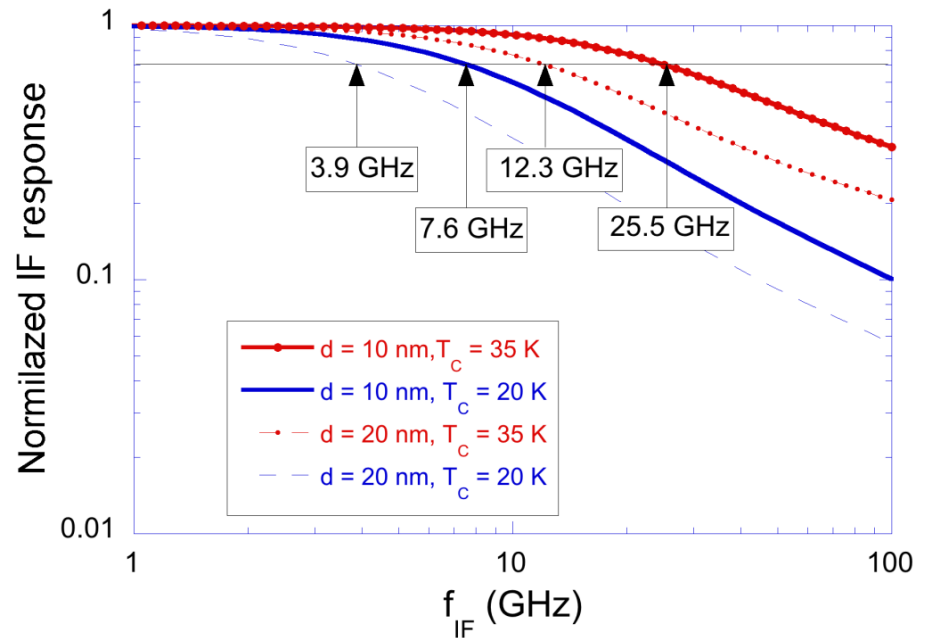
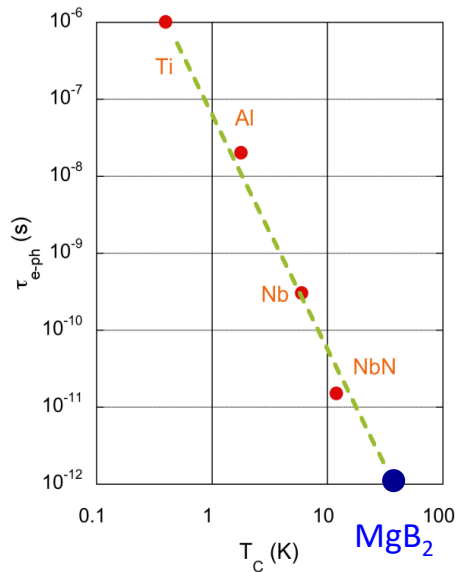


H. J. Choi et al., Nature **418**, 758 (2002).



MgB₂ Potential for HEB Applications

Material	MgB ₂	NbN	MgO	SiC	Si
ρ (g cm ⁻³)	2.7	8.5	3.6	3.2	2.3
v_s (km/s)	7.8	2.5	6.6	7.5	6
Z_a (10 ⁶ kg m ⁻² s ⁻¹)	21	21	24	24	14



- Well acoustically matched to substrates of interest.
- 2-Temperature model predictions yield small effective τ which will result in a large intermediate frequency (IF) bandwidth.
- Additional benefit of variable resistivity for impedance matching.

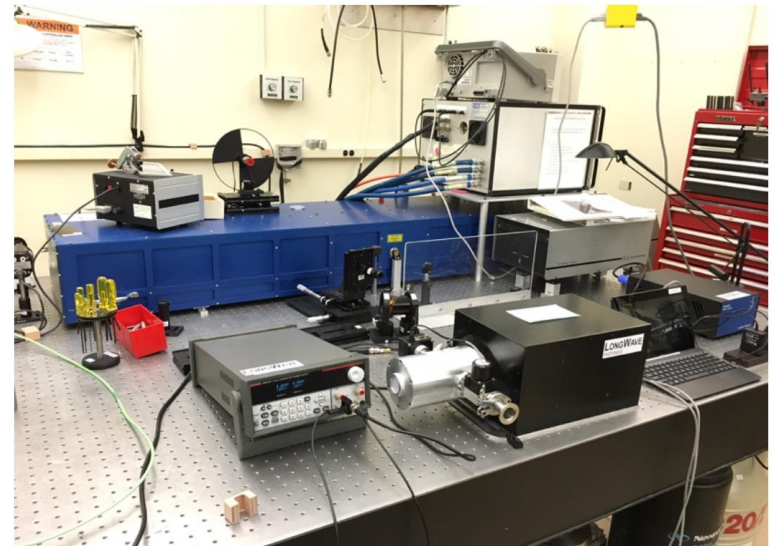
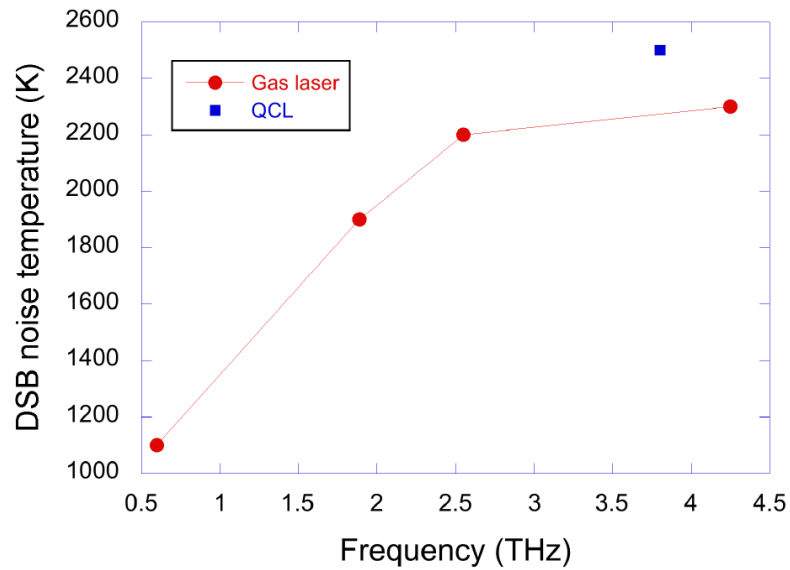
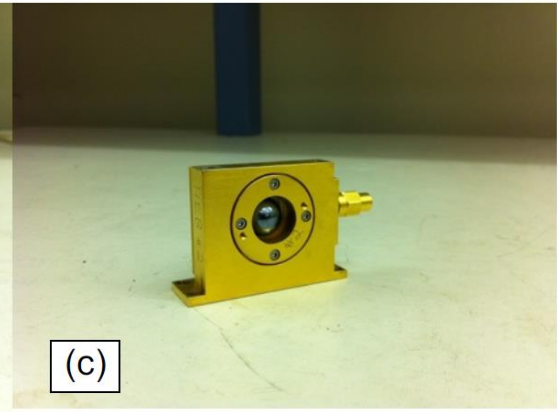
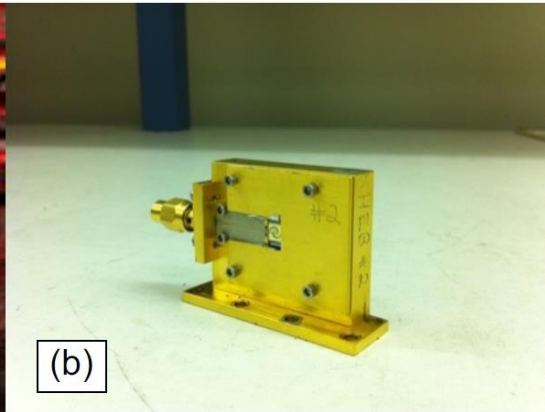
Comparison to SOA at 4.7 THz

Parameter	SOA NbN HEB mixer		Current MgB ₂ QO HEB mixer
	WG	QO	
DSB noise temp. (K)	1100	815	2300 @4.3 THz
IF noise BW (GHz)	≈ 3	≈ 3	≈ 7
Operating temp. (K)	4.6	4.2	15
Array size	1 × 1	1 × 1	1 × 1
LO type	QCL	QCL	far-IR laser

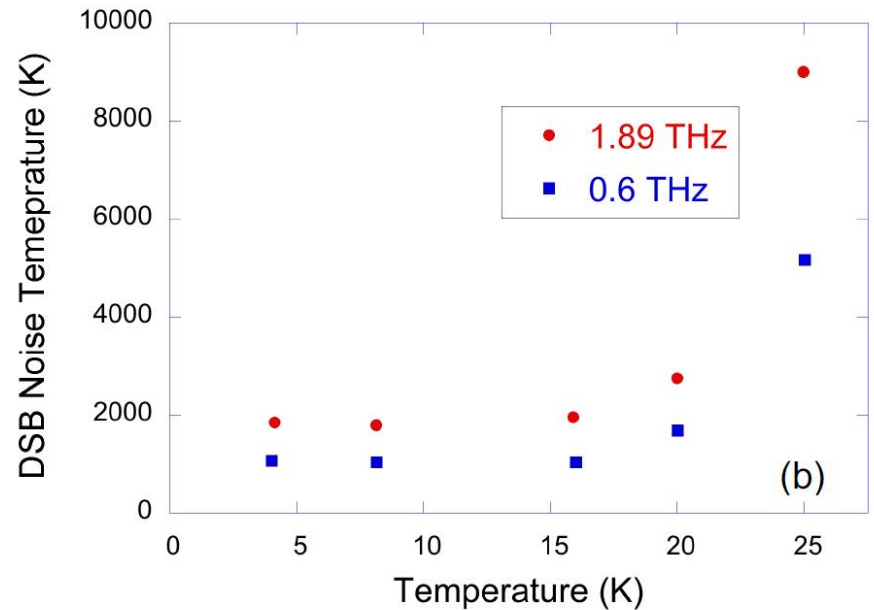
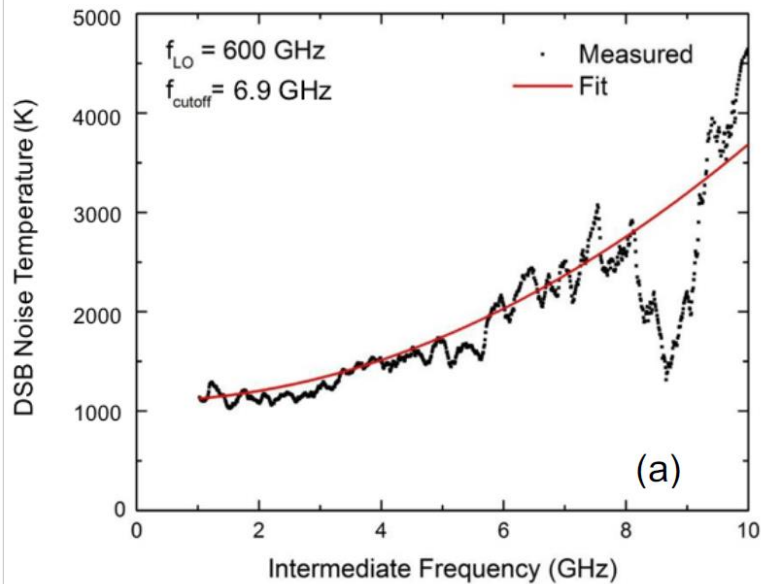
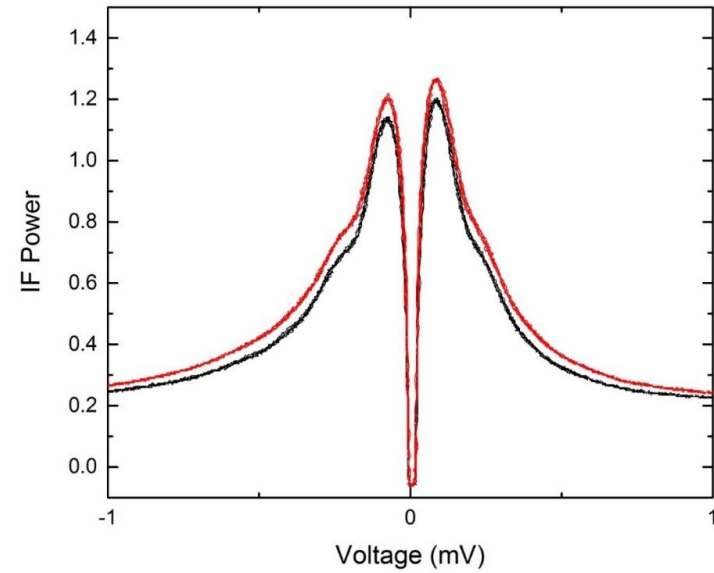
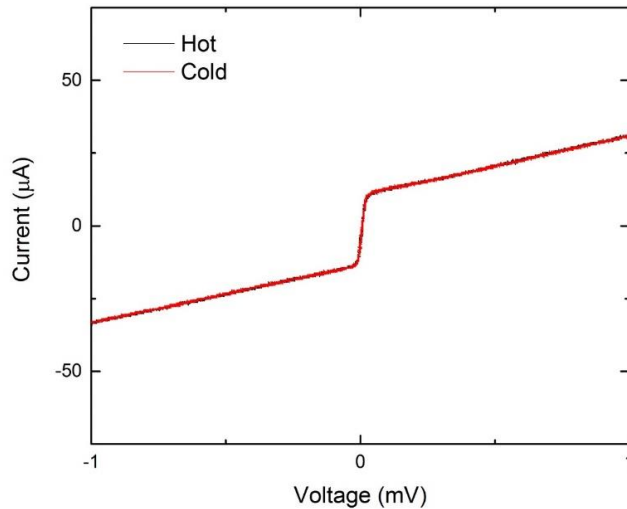
WG) D. Büchel *et al.*, "4.7-THz Superconducting Hot Electron Bolometer Waveguide Mixer," *IEEE Trans. THz Sci. Technol.*, vol. 5, no. 2, pp. 207-214, 2015.

QO) J. L. Kloosterman *et al.*, "Hot electron bolometer heterodyne receiver with a 4.7-THz quantum cascade laser as a local oscillator," *Appl. Phys. Lett.*, vol. 102, p. 011123, 2013.

MgB₂ Quasi-Optical Mixers

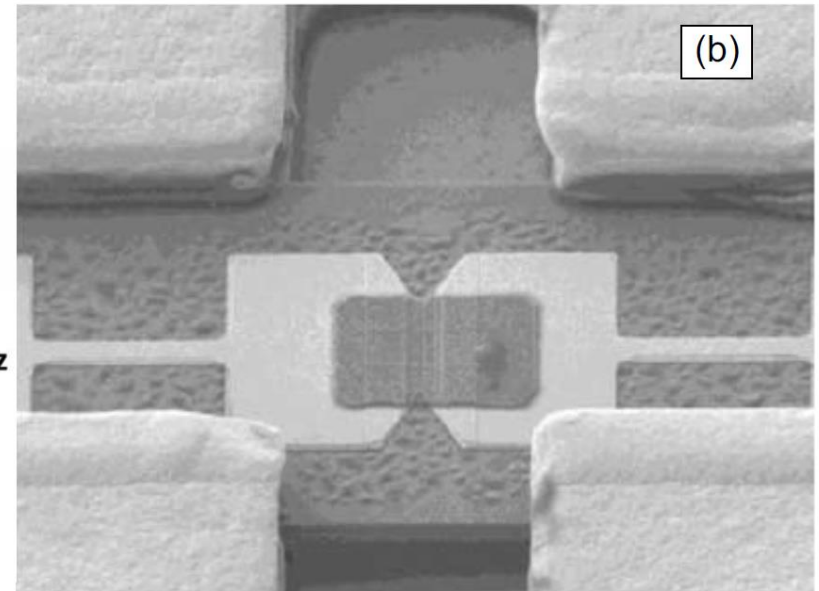
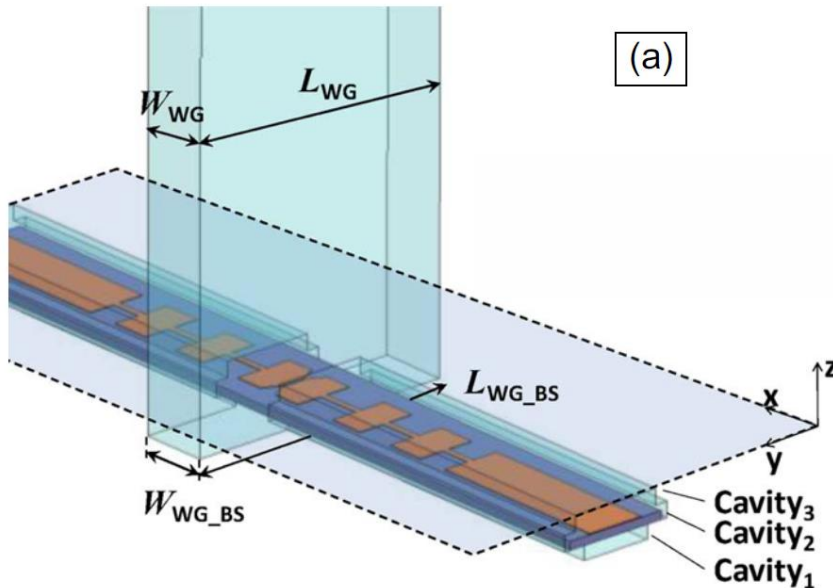
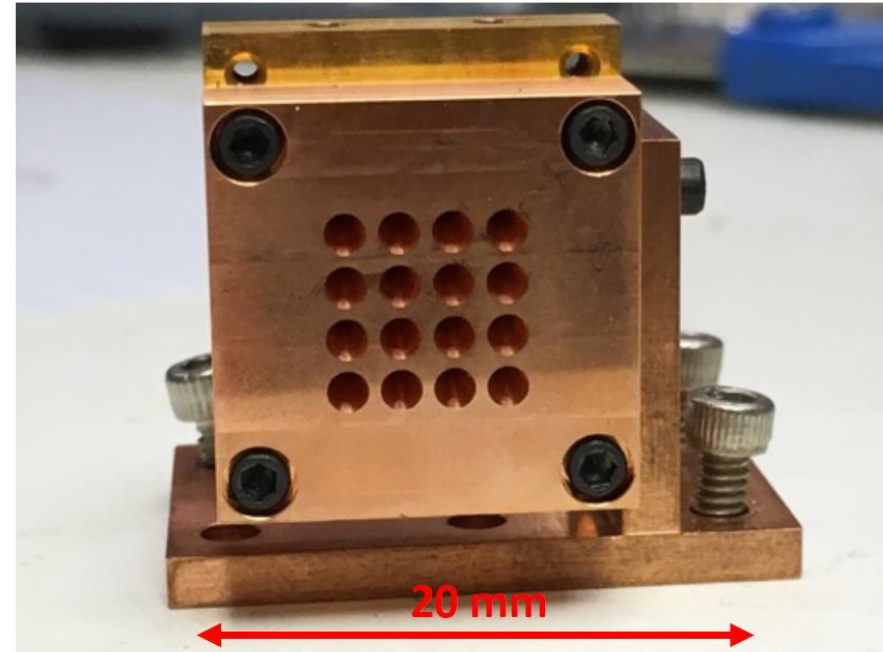


MgB₂ Quasi-Optical Mixers

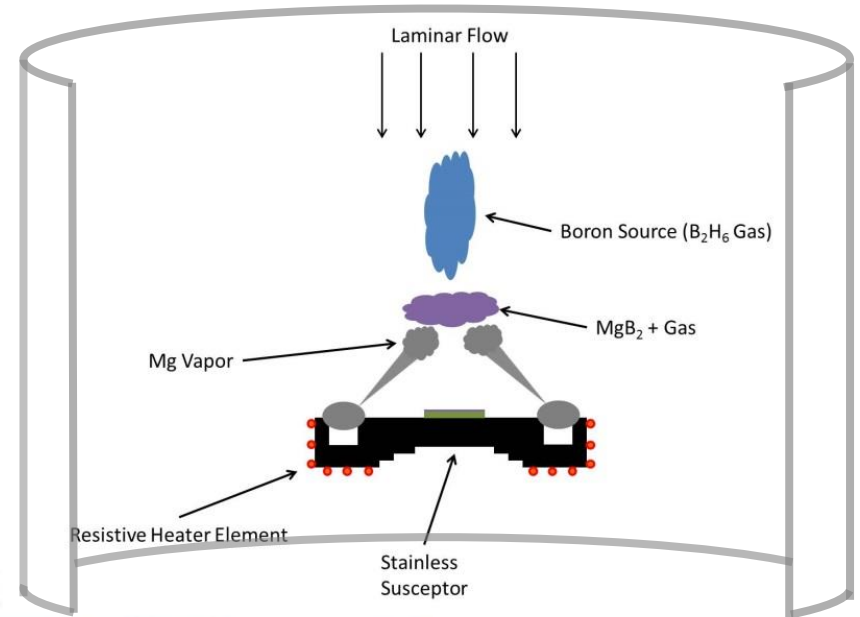


Goal: Waveguide Mixers

- Need to develop devices on SOI substrates with 3-6 μm device layer thickness.
- Need to show that backside alignment and etch of the handle wafer do not effect device performance.



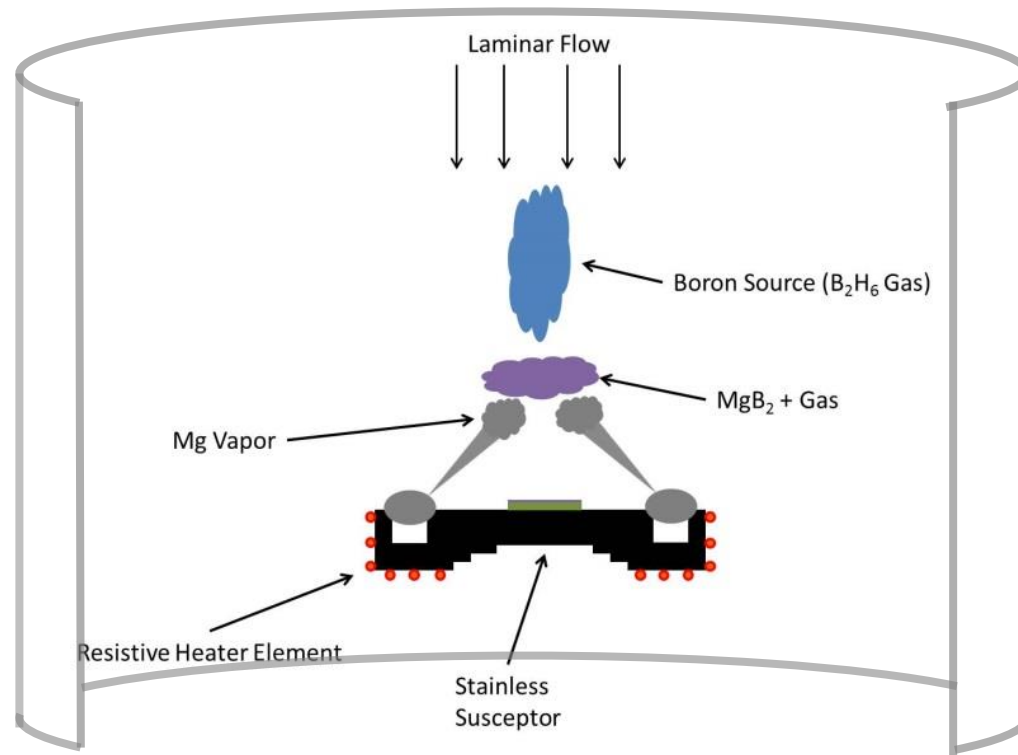
HPCVD Grown MgB_2 Thin Films



700 C and 40 Torr

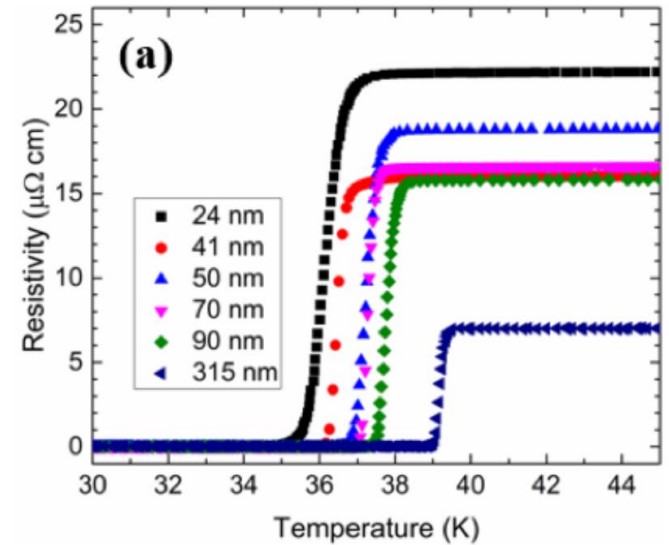
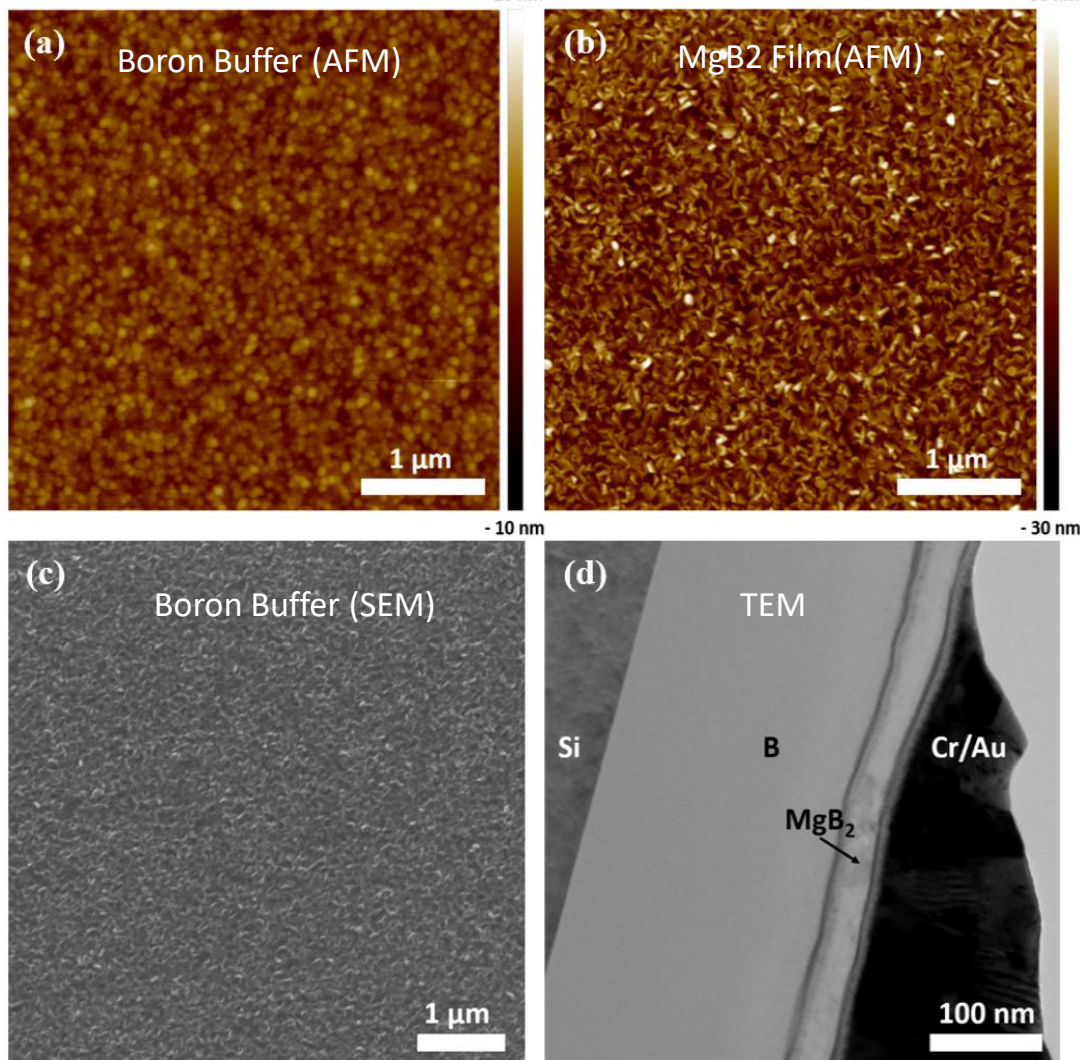


CVD Boron Thin Films as a Buffer



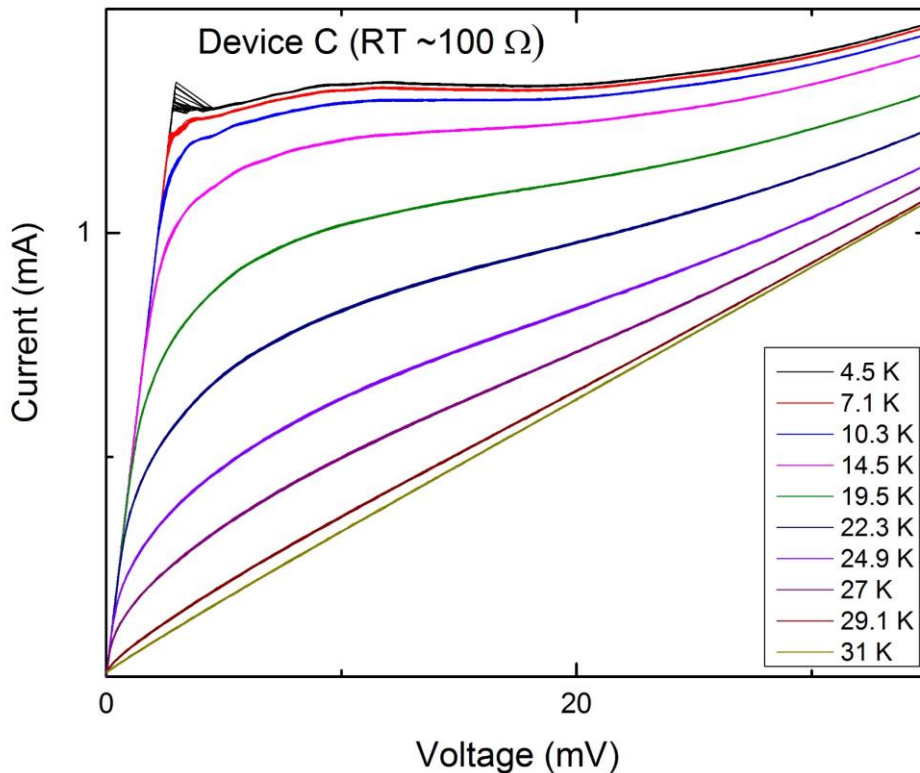
- Obstacle: Reaction between Si and Mg around 450 C
- Solution: Intermediate Buffer layer
 - MgO was the first choice, but smooth MgO films cracked during higher temperature MgB₂ deposition
 - Boron films first used to grow MgB₂ on Cu (same issue) for SRF applications.

Films on Si Substrate



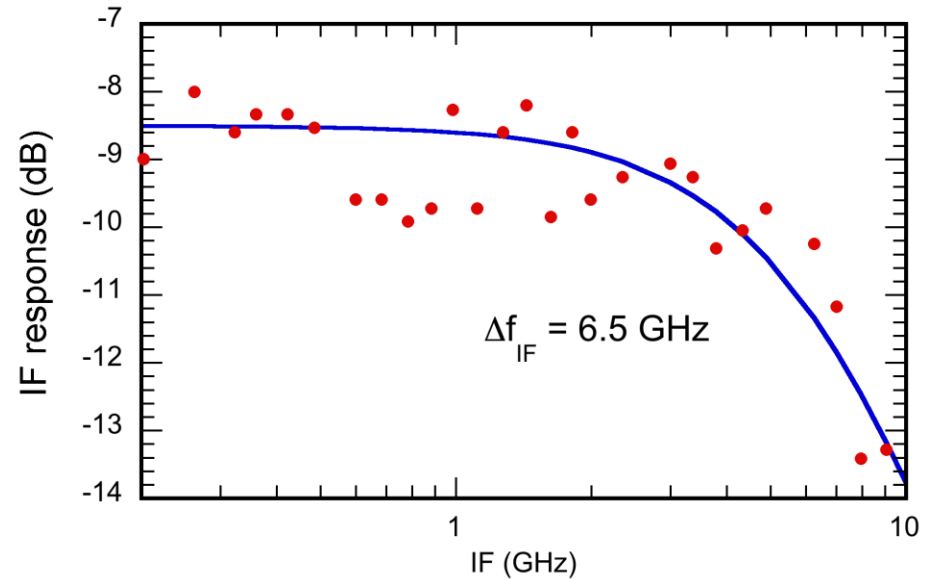
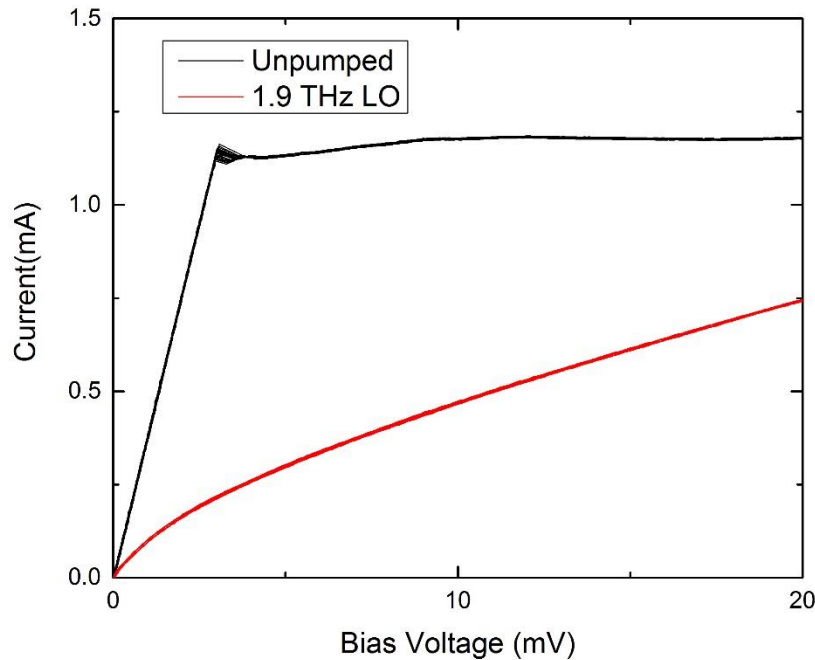
- Poor Roughness of Boron films lead to poor roughness of MgB₂ films.
- Very clean interfaces implies room for improvement.

HEB Devices on Si Substrate (DC characterization)



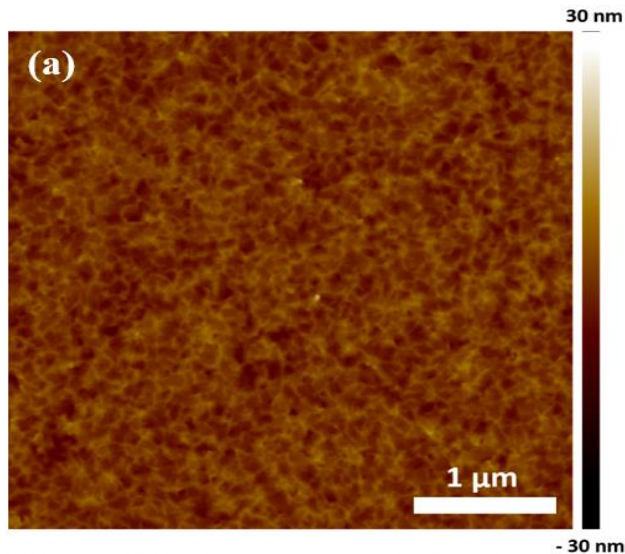
- 20 nm Film
- T_c corresponds with what was seen for Films
- ΔT_c is ~ 4 K, leading to poor sensitivity (expected problem is from film non-uniformity)
- J_c is a factor of 2 lower than bare films (6 MA/cm^2 compared to $>10 \text{ MA/cm}^2$ in films)

HEB Devices on Si Substrate (RF characterization)

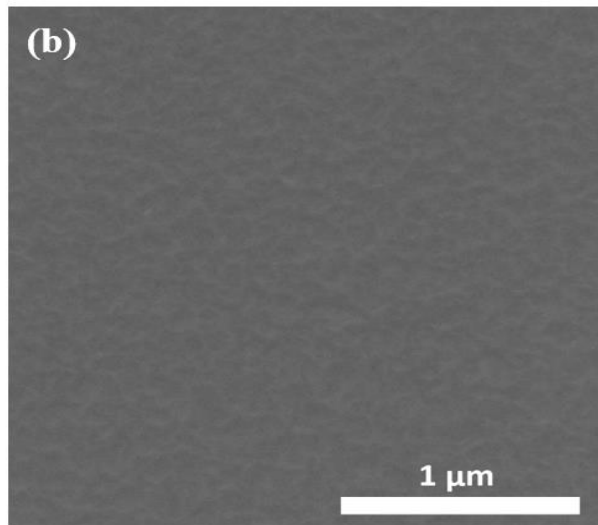
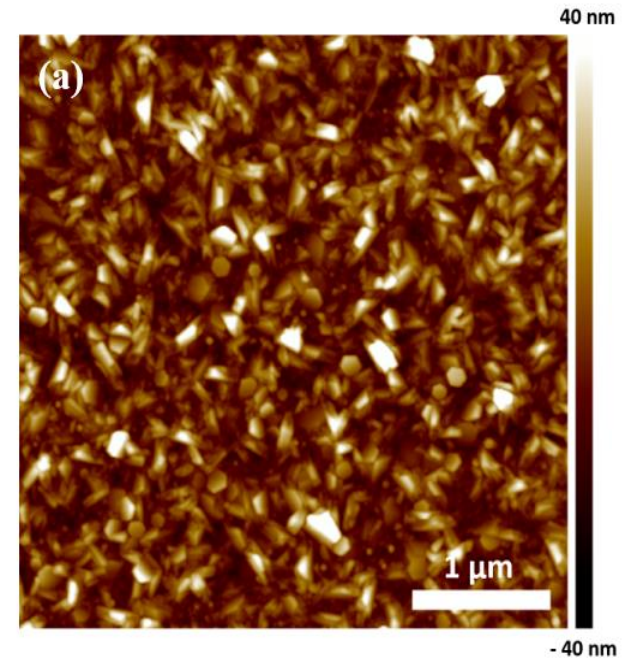


- THz pumping of devices is easier than previous devices.
 - Device T_c is somewhat lower
 - Impedance matching is improved (low temp device resistance approx. 30 ohms)
- Gain bandwidth measurement done with microwave frequencies.
 - Bandwidth identical to device on SiC substrate with similar film thickness (6.5 GHz).

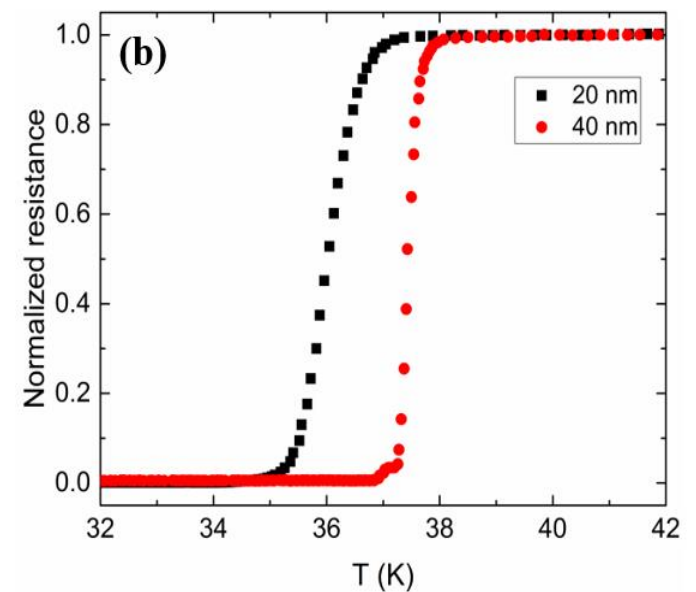
Optimization of Films and Growth on SOI



Ion milling at a very shallow angle can improve the roughness significantly (factor of 2-5). This was used to achieve ~ 3 nm films with $T_c > 30$ K.



Films can be grown on SOI substrates without any further degradation of the SC properties.



Summary:

- Consistently see an IF bandwidth around 7 GHz for a 15 nm film
 - Bandwidth confirmed even when moving to the polycrystalline films on Si Substrates.
- Noise temperature of MgB2 HEBs about 2x larger than SOA NbN devices
 - Still significant room for improvement, particularly with impedance matching
 - NT of MgB2 HEBs on Si Substrate needs further work, particularly, more uniform films to achieve smaller ΔT_c .
 - Polycrystalline films on Si have larger sheet resistance which will make impedance matching easier.
- MgB2 films have been grown on SOI substrates and efforts are under way to fabricate some WG coupled HEBs for frequencies from 1.9 THz to 4.7 THz.